Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/800,884	ZHANG ET AL.	
Examiner	Art Unit	
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Class	Subclass	Date	Examiner
455	456.1 457 566	11/3/2007	СТ
340	995.12	11/3/2007	СТ
	539.13		
	825.49		

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH (INCLUDING SEA	H NOTES ARCH STRATEGY	′)
	DATE	EXMR
Search Updated	11/3/2007	СТ
